

## SHENZHEN LONG JING MICRO-ELECTRONICS CO., LTD.

# **SOT-23 Plastic-Encapsulate MOSFETS**

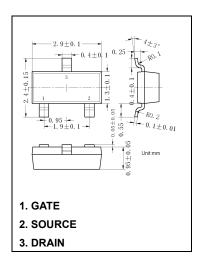
SI2302 N-Channel 20V(D-S) MOSFET

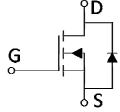
#### **Features**

- $\blacksquare$  V<sub>DS</sub> = 20V, I<sub>D</sub> = 2.5A
- $R_{DS(ON)}$  < 115m $\Omega$  @  $V_{GS}$  = 2.5V
- $R_{DS(ON)} < 85m\Omega$  @  $V_{GS} = 4.5V$
- Super high density cell design for extremely low R<sub>DS(ON)</sub>
- Exceptional on-resistance and maximum DC current capability

## **Applications**

- Power Management in Note book
- Portable Equipment
- Battery Powered System
- Load Switch
- DSC





#### **Description**

The SI2302 is the N-Channel logic enhancement mode power field effect transistors are produced using high cell density, DMOS trench technology. This high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage application such as cellular phone and notebook computer power management and other battery powered circuits where high-side switching and low in-line power loss are needed in a very small outline surface mount package.

#### Marking: A2SHB.

### Maximum Ratings (T<sub>a</sub>=25 °C unless otherwise noted)

Symbol	Parameter	Value	Unit	
V <sub>DS</sub>	Drain-source voltage	20	V	
V <sub>GS</sub>	Gate-source voltage	±8	V	
I <sub>D</sub>	Continuous drain current	2.5	А	
I <sub>DM</sub>	Pulsed Drain Current 1)	10		
P <sub>D</sub>	Power dissipation	0.9	W	
TJ	Operating Junction	150	°C	
T <sub>stg</sub>	Storage temperature	-55 to 150	°C	

#### **Thermal Characteristic**

Symbol	Parameter	Value	Unit
Reja	Thermal Resistance from Junction to Ambient (t $\leq$ 5s) <sup>2)</sup>	139	°C /W

# **Electrical Characteristics (T<sub>a</sub>=25 °C unless otherwise noted)**

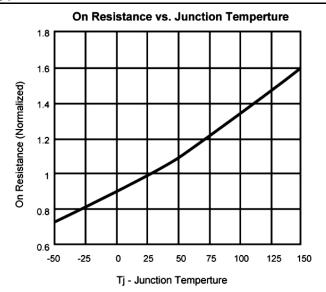
Symbol	Parameter	Test conditions	Min	Тур	Max	Unit			
Off Characteristics									
V <sub>(BR)DSS</sub>	Drain- source breakdown voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250uA	20			V			
I <sub>DSS</sub>	Zero gate voltage drain current	V <sub>DS</sub> = 20V, V <sub>GS</sub> = 0V			1	μΑ			
I <sub>GSS</sub>	Gate-body leakage current	$V_{GS} = \pm 8V$ , $V_{DS} = 0V$			±100	nA			
On Chara	On Characteristics								
$V_{GS(th)}$	Gate threshold voltage	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = 250uA	0.5		1.2	V			
R <sub>DS(on)</sub>	Drain-Source on-state resistance	$V_{GS} = 4.5V, I_D = 2.5A$		55	85	mΩ			
		$V_{GS} = 2.5V, I_D = 2.0A$		65	115				
Dynamic	Characteristics								
Ciss	Input capacitance	V 0.V V 40V		450		pF			
Coss	Output capacitance	$V_{GS} = 0 \text{ V}, V_{DS} = 10 \text{V},$ $f = 1 \text{MHz}$		72					
C <sub>rss</sub>	Reverse transfer capacitance	1 111112		22					
Switching Characteristics									
t <sub>d(on)</sub>	Turn-on delay time			9		ns			
tr	Rise time	$V_{DD}$ = 10V, $R_L$ =10 $\Omega$ $V_{GEN}$ = 4.5 $\Omega$ , $R_G$ =6 $\Omega$		23					
t <sub>d(off)</sub>	Turn-off delay time			38					
t <sub>f</sub>	Fall time			3					
Qg	Total gate charge			9		nC			
Qgs	Gate-source charge	$V_{DS} = 10V$ , $V_{GS} = 4.5V$ , $I_{D} = 2.5A$		2.2					
Q <sub>gd</sub>	Gate-drain charge			3					
Drain-source body diode characteristics									
V <sub>SD</sub>	Diode forward voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 1A		0.75	1.2	V			

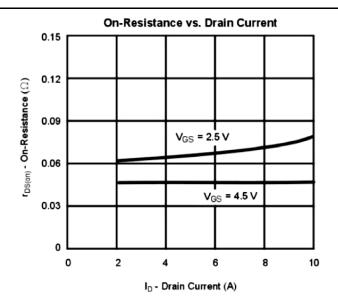
#### Notes:

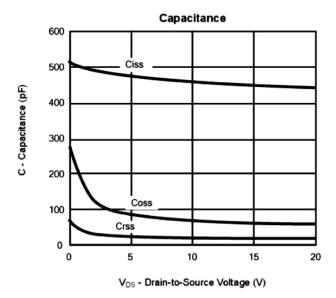
<sup>1.</sup> Repetitive Rating: Pulse width limited by maximum junction temperature.

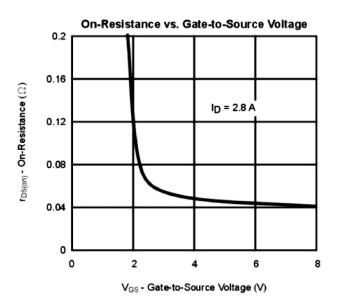
<sup>2.</sup> Surface Mounted on FR4 Board,  $t \le 10$  sec.

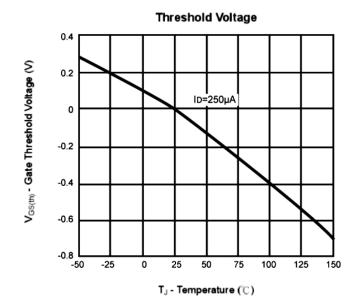
## **Typical Electrical and Thermal Characteristics**

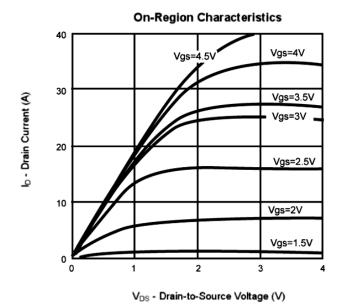












## Typical Electrical and Thermal Characteristics(Cont.)

